## Notice of References Cited Application/Control No. 10/622,085 Examiner Liang-che Alex Wang Applicant(s)/Patent Under Reexamination FURUTONO ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,807,148	10-2004	Eicher, David E.	370/217
*	В	US-6,614,126	09-2003	Mitchell, James P.	307/9.1
*	C	US-5,745,159	04-1998	Wax et al.	725/76
*	D	US-6,208,640	03-2001	Spell et al.	370/358
*	Ε	US-2003/0035386	02-2003	Sullivan, Mark	370/316
*	F	US-2003/0024988	02-2003	Stanard, David	235/462.01
*	G	US-2003/0140131	07-2003	Chandrashekhar et al.	709/223
	Н	US-			
	ı	US-			
	J	US-			
	К	US- '			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2002027453 A	01-2002	Japan	EDA et al.	
	0					
	Р					
	Q					·
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)							
	U								
	V								
	w								
·	x								

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.